Improved Stability of Organic Light-Emitting Diodes using Nickel Oxide doped PEDOT:PSS

Jiho Sohn¹, Yongwon Kwon¹ and Changhee Lee¹ ¹Department of Electrical and Computer Engineering, Inter-university Semiconductor Research Center, Seoul National University, 1 Gwanak-ro, Gwanak-gu, Seoul 151-744, Korea *Tel.*:82-2-880-9593. *E-mail: chlee@snu.ac.kr*

Poly(ethylenedioxythiophene) doped with poly(styrenesulfonate) (PEDOT :PSS) is one of the most interesting and studied materials in optoelectronic devices for its high conductivity, high transparency in the visible range and high workfunction[1]. It has been widely used as hole injection layer (HIL) on top of the anode in organic lightemitting diodes (OLEDs). However, PEDOT :PSS have several limitations especially that the nature of its acidity affects the organic/inorganic interface, leading to device failure[2]. Therefore, transition oxide materials such as MoO_3 and WO_3 have been used to avoid this problem [3-4]. Here, we have investigated the effect of sol-gel nickel-oxide (NiO_x) doping in PEDOT:PSS (PEDOT:PSS:NiO_x), specifically in terms of the OLED device stability.

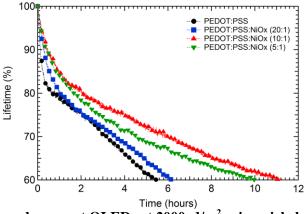


Fig. 1. Lifetime of green phosphorescent OLEDs at 2000cd/m² using nickel-oxide doped PEDOT:PSS as HIL with different doping concentrations

NiO_x thin films are p-type and transparent semiconductor with a band gap energy in the range of 3.6-4.0eV. The sol-gel processed NiO_x has a deep LUMO level above 2eV which can be stable in air without being oxidized. Therefore, we have adopted sol-gel NiO_x doped in PEDOT:PSS to improve OLED device stability. The effect of NiO_x doping in PEDOT:PSS have been demonstrated using green phosphorescent emitter tris[2-phenylpyridinato-C2]iridium(III) (Ir(ppy)₃) doped in 4, 4'-Bis(N-carbazolyl)-1,1'-biphenyl (CBP) with different NiO_x doping concentrations. The device stability was measured through operation lifetime, fixing the initial luminance at 2000cd/m² and supplying constant current to each device (Fig. 1). The device with 10:1 volume ratio of PEDOT:PSS:NiO_x exhibited extrapolated half-lifetime (LT50) of 14.3 hours, improving the operation lifetime nearly 200% compared to that of reference PEDOT:PSS (LT50 = 7.5 hours).

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References

- 1. J. Huang, P. F. Miller, J. S. Wilson, A. J. de Mello and D. D. C. Bradley, Adv. Funct. Mater. 15(2), 290 (2005).
- 2. M. Joergensen, K. Norrman, S. A. Gevorgyan, T. Tromholt, B. Andreasen and F. C. Krebs, *Adv. Mater.* 24(5), 580 (2012).
- 3. Y. Kwon, Y. Kim, H. Lee, C. Lee and J. Kwak, Org. Electron. 15(6), 1083 (2014)
- 4. Z. Tan, L. Li, C. Cui, Y. Ding, Q. Xu, S. Li, D. Qian and Y. Li, J. Phys. Chem. C. 115(35), 18626 (2012)